

## FIS920030146US1 / U.S. Serial No. 10/604,989 Stephen W. Bedell et al. / LJJ "AN ELECTRON MICROSCOPE MAGNIFICATION STANDARD PROVIDING PRECISE CALIBRATION IN THE MAGNIFICATION RANGE 5000X-200,000X" 1/5

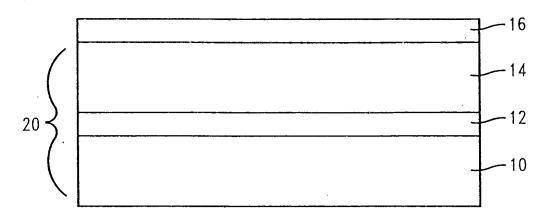


FIG. 1

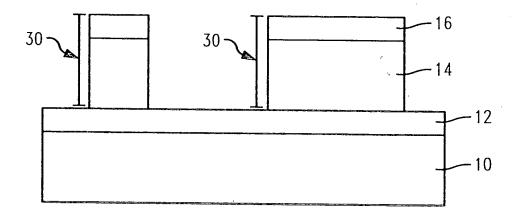


FIG. 2

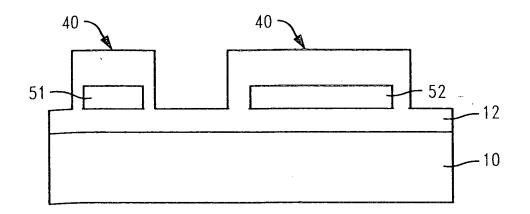
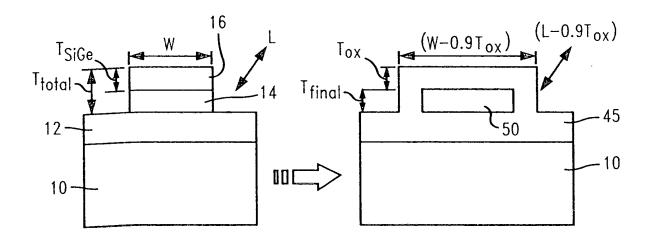
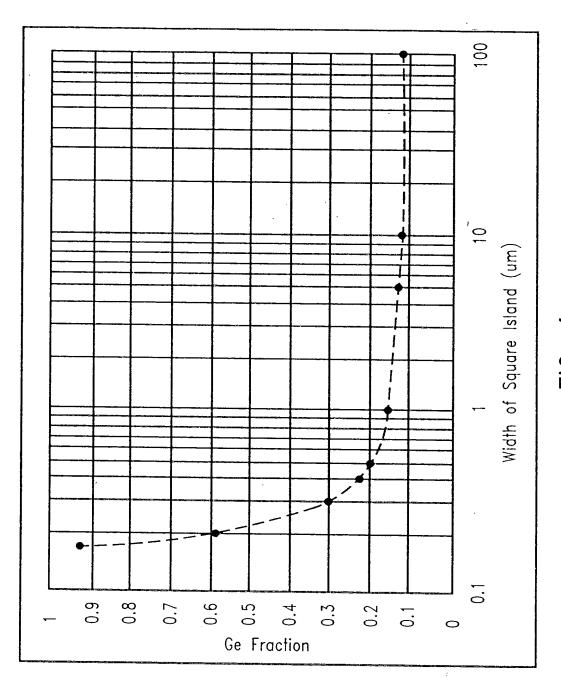


FIG. 3A

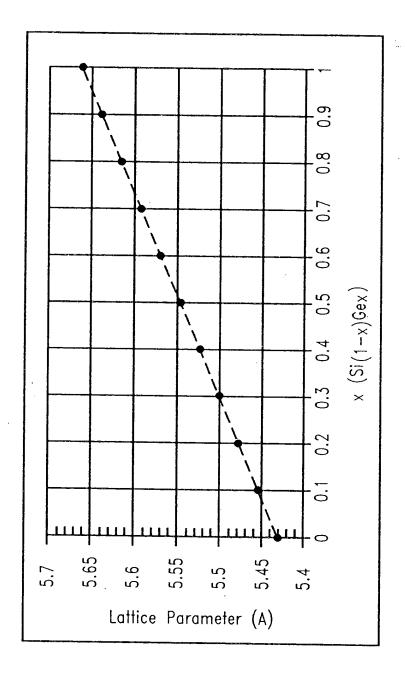


$$x_{SGOI} = \frac{(LWt_{SiGe} \times SiGe)}{(L-0.9t_{Ox})(W-0.9t_{Ox})(t_{Total}-0.45t_{Ox})}$$

FIG. 3B



F 6. 4



F.G. 5

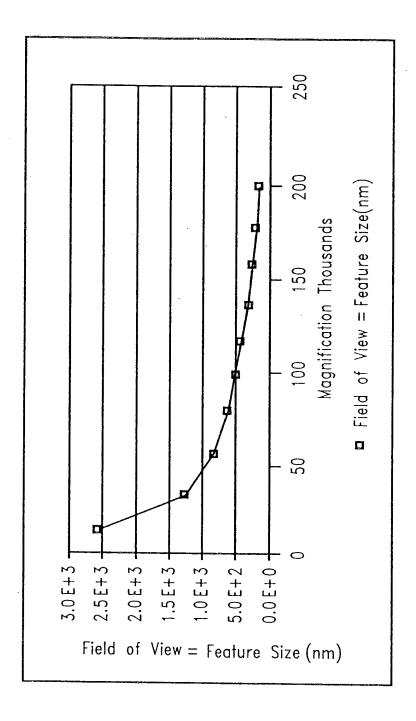


FIG. 6